Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/617,113	CHOWN, DAVID
Examiner	Art Unit
Leslie Pascal	2613

SEARCHED				
Class	Subclass	Date	Examiner	
398	135-139	11/7/2006	LP	
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	<u> </u>			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			•	
SEE SEAR	CH NOTES	2/24/2007	LP	

SEAR( (INCLUDING SE	CH NOTES EARCH STRATEGY	<b>(</b> )
	DATE .	
see search notes	11/6/2007	LP
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